Search Notes		

Application/Control No.	Applicant(s)/Patent un Reexamination	nt under	
10/615,021	CHANG, WON-KIL		
Examiner	Art Unit		
Shih-wen Hsieh	2861		

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Class	Subclass	Date	Examiner
347	1,22,29 30,32,33 81	5/19/2005	SWH
15	250.361	5/19/2005	SWH
101	155	5/19/2005	SWH
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INT	INTERFERENCE SEARCHED		
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